



# Baliga's FOM

Baliga, B.J. "Advanced Power MOSFET Concepts"

$$g_{n,D} = \frac{\epsilon E_{crit}^2}{2V_{BV}}$$

$$R_{on,sp} = \sqrt{\frac{2\epsilon V_{BV}}{q n^2}} \sqrt{\frac{1}{(\frac{\epsilon E_{crit}^2}{2V_{BV}})^3}} = \sqrt{\frac{2^4 V_{BV}^4}{q n^2 \epsilon^2 E_{crit}^6}} = \sqrt{\frac{4 V_{BV}^2}{q n \epsilon E_{crit}^3}}$$

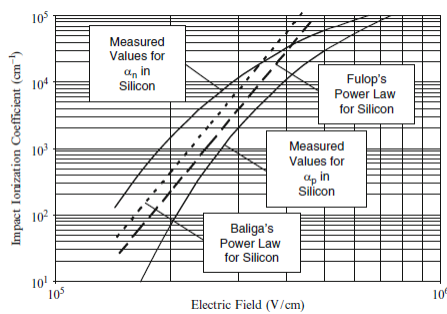
(max doping density to have  $E_{max} \leq E_{crit}$ )

"Ideal" specific on-resistance

Baliga's Figure of Merit ↑



# Note: Impact Ionization

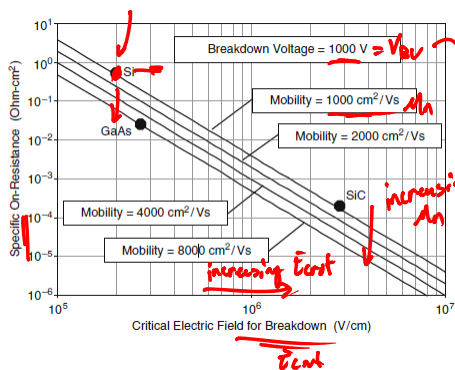


$\alpha =$  Impact ionization coefficient ( $\frac{1}{cm}$ )  
 Empirically modeled as  
 $\alpha = k_1 E^n$   
 Definition of Breakdown:  
 $\int_0^{W_D} \alpha dx = 1$   
 from our analysis:  $E = \frac{\delta_{CB}}{\epsilon} x + \frac{\delta_{DB}}{\epsilon} W_D$   
 $1 = \int_0^{W_D} k_1 \left( \frac{\delta_{CB}}{\epsilon} x + \frac{\delta_{DB}}{\epsilon} W_D \right)^n dx$   
 Phy in  $E_{max} = \frac{\delta_{DB}}{\epsilon} W_D$

$W_{PP,B}(Si) = 2.404 \times 10^{10} N_D^{-7/8}$   
 $E_{C,1D,B}(Si) = 3,700 N_D^{1/8}$



# Ideal Specific On-Resistance



$\uparrow V_{BSV} \Rightarrow \uparrow R_{on,sp}$  (square)  
 (Very high voltage Majority  $\rightarrow$  minority carrier devices)  
 Tradeoffs: Area  
 $\uparrow A \Rightarrow \downarrow R, \uparrow C$

Baliga, B J, "Advanced Power MOSFET Concepts"



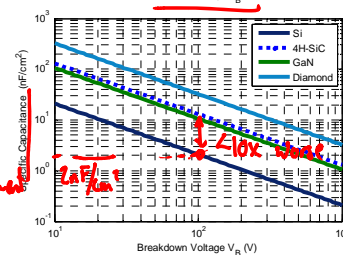
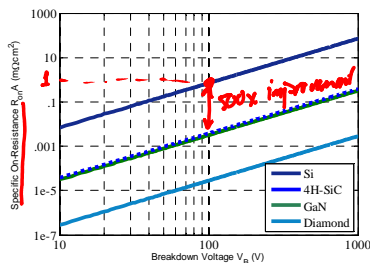
# WBG Materials

Table 2.1. Physical characteristics of Si and the major WBG semiconductors

Property	Si	GaAs	4H-SiC	4H-SiC	GaN	Diamond
Bandgap, $E_g$ (eV)	1.12	1.43	3.03	3.26	3.45	5.45
Dielectric constant, $\epsilon_r^a$	11.9	13.1	9.66	10.1	9	5.5
Electric breakdown field, $E_b$ (kV/cm)	300	400	2,500	2,200	2,000	10,000
Electron mobility, $\mu_n$ (cm²/V·s)	1,500	8,500	500	1,000	1,250	2,200
Hole mobility, $\mu_p$ (cm²/V·s)	600	400	101	115	850	850
Thermal conductivity, $\lambda$ (W/cm·K)	1.5	0.46	4.9	4.9	1.3	22
Saturated electron drift velocity, $v_{sat}$ ( $\times 10^7$ cm/s)	1	1	2	2	2.2	2.7

<sup>a</sup>  $\epsilon = \epsilon_r \cdot \epsilon_0$ , where  $\epsilon_0 = 8.85 \times 10^{-14}$  F/cm.

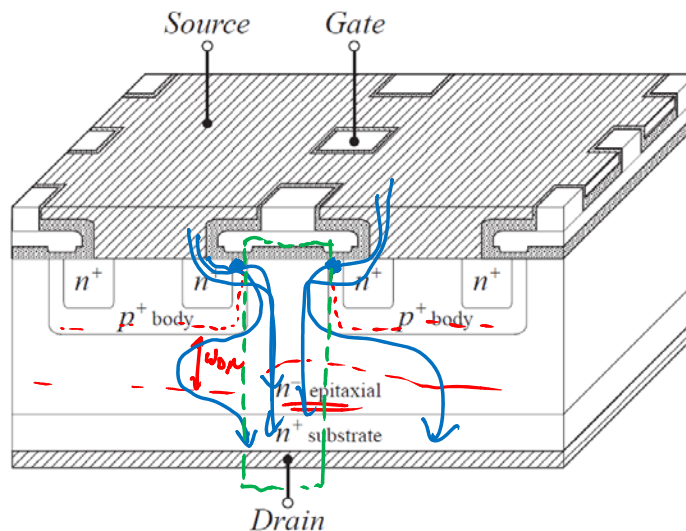
B Ozpineci, L M Tolbert, "Comparison of Wide-Bandgap Semiconductors for Power Electronics Applications"



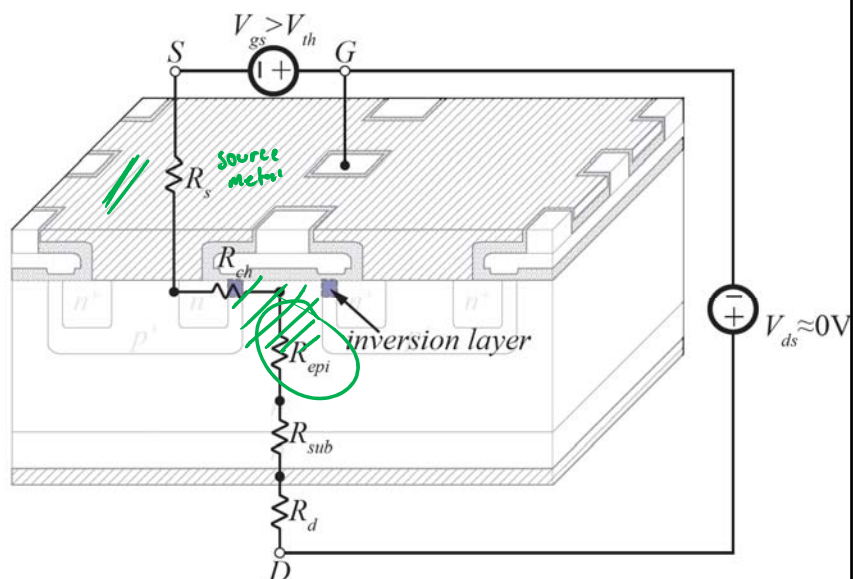
example Form:  $R_{on,sp} C_{sp}$  (nS·pF/cm²)  
 from Si  $\rightarrow$  GaN  
 $R_{on,sp} C_{sp} \rightarrow 50x$  improvement



## MOSFET Cross Section



## MOSFET On-Resistance





# Resistance Contributions Vs. Voltage

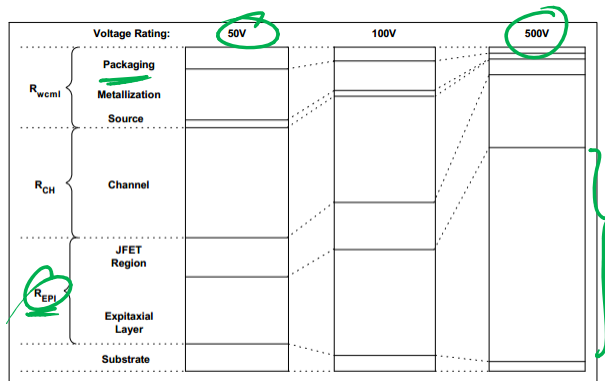
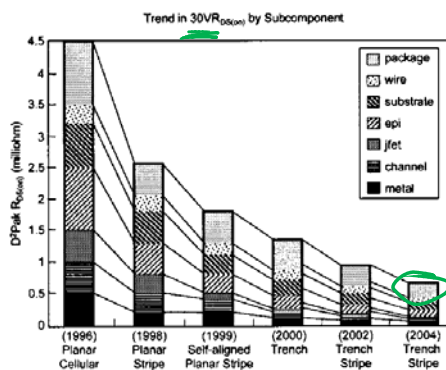


Figure 9. Relative Contributions to  $R_{DS(on)}$  With Different Voltage Ratings.

V. Barkhordarian et al. "Power MOSFET Basics"



# Resistance Contributions



A. Lidow et al. "The Semiconductor Roadmap for Power Management in the New Millennium"